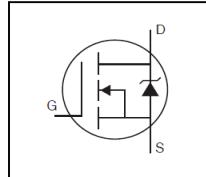


**Features**

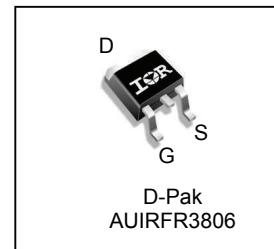
- Advanced Process Technology
- Ultra Low On-Resistance
- Dynamic dV/dT Rating
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to Tjmax
- Lead-Free, RoHS Compliant
- Automotive Qualified \*



HEXFET® Power MOSFET		
$V_{DSS}$		60V
$R_{DS(on)}$	typ.	12.6mΩ
	max.	15.8mΩ
$I_D$		43A

**Description**

Specifically designed for Automotive applications, this HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating . These features combine to make this design an extremely efficient and reliable device for use in Automotive applications and a wide variety of other applications.



G	D	S
Gate	Drain	Source

Base part number	Package Type	Standard Pack		Orderable Part Number
		Form	Quantity	
AUIRFR3806	D-Pak	Tube	75	AUIRFR3806
		Tape and Reel Left	3000	AUIRFR3806TRL

**Absolute Maximum Ratings**

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified.

Symbol	Parameter	Max.	Units
$I_D @ T_c = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	43	A
$I_D @ T_c = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	31	
$I_{DM}$	Pulsed Drain Current ①	170	
$P_D @ T_c = 25^\circ C$	Maximum Power Dissipation	71	W
	Linear Derating Factor	0.47	W/°C
$V_{GS}$	Gate-to-Source Voltage	± 20	V
$E_{AS}$	Single Pulse Avalanche Energy (Thermally Limited) ②	73	mJ
$I_{AR}$	Avalanche Current ①	25	A
$E_{AR}$	Repetitive Avalanche Energy ①	7.1	mJ
$dv/dt$	Peak Diode Recovery dv/dt③	24	V/ns
$T_j$	Operating Junction and	-55 to + 175	°C
$T_{STG}$	Storage Temperature Range		
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	

**Thermal Resistance**

Symbol	Parameter	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case ④	—	2.12	°C/W
$R_{\theta JA}$	Junction-to-Ambient ( PCB Mount) ⑦	—	50	
$R_{\theta JA}$	Junction-to-Ambient ⑦	—	110	

HEXFET® is a registered trademark of Infineon.

\*Qualification standards can be found at [www.infineon.com](http://www.infineon.com)

**Static @  $T_J = 25^\circ\text{C}$  (unless otherwise specified)**

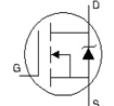
	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(\text{BR})\text{DSS}}$	Drain-to-Source Breakdown Voltage	60	—	—	V	$V_{GS} = 0V, I_D = 250\mu\text{A}$
$\Delta V_{(\text{BR})\text{DSS}}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.075	—	V/ $^\circ\text{C}$	Reference to $25^\circ\text{C}, I_D = 5\text{mA}$ ①
$R_{DS(\text{on})}$	Static Drain-to-Source On-Resistance	—	12.6	15.8	$\text{m}\Omega$	$V_{GS} = 10\text{V}, I_D = 25\text{A}$ ④
$V_{GS(\text{th})}$	Gate Threshold Voltage	2.0	—	4.0	V	$V_{DS} = V_{GS}, I_D = 50\mu\text{A}$
$g_{fs}$	Forward Trans conductance	41	—	—	S	$V_{DS} = 10\text{V}, I_D = 25\text{A}$
$R_{G(\text{Int})}$	Internal Gate Resistance	—	0.79	—	$\Omega$	
$I_{DSS}$	Drain-to-Source Leakage Current	—	—	20	$\mu\text{A}$	$V_{DS} = 60\text{V}, V_{GS} = 0\text{V}$
		—	—	250		$V_{DS} = 48\text{V}, V_{GS} = 0\text{V}, T_J = 125^\circ\text{C}$
$I_{GSS}$	Gate-to-Source Forward Leakage	—	—	100	$\text{nA}$	$V_{GS} = 20\text{V}$
	Gate-to-Source Reverse Leakage	—	—	-100		$V_{GS} = -20\text{V}$

**Dynamic Electrical Characteristics @  $T_J = 25^\circ\text{C}$  (unless otherwise specified)**

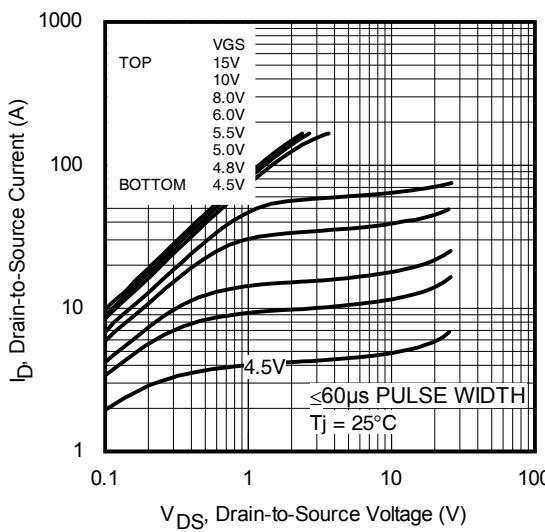
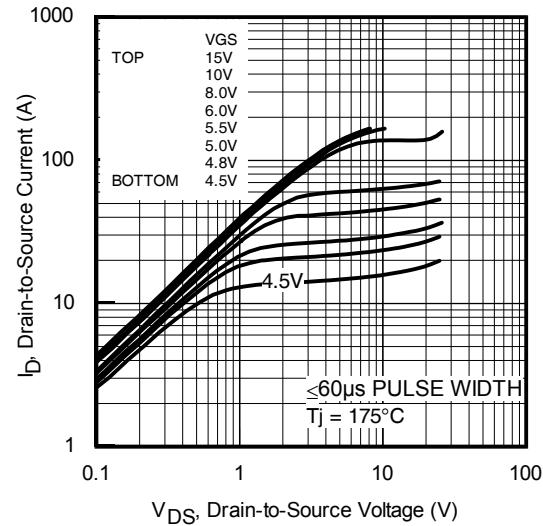
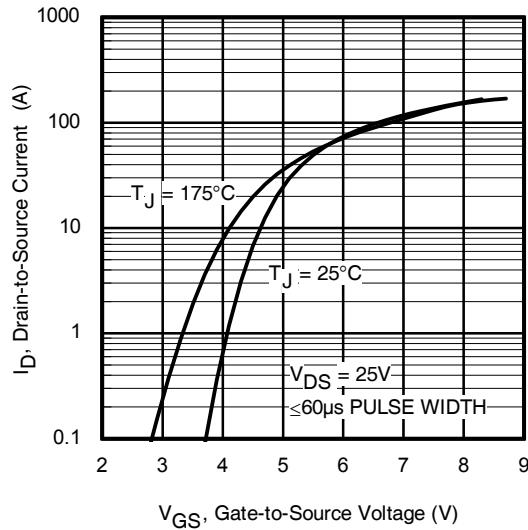
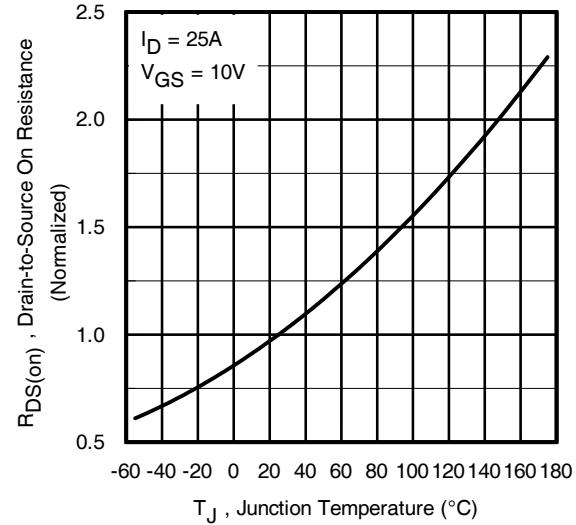
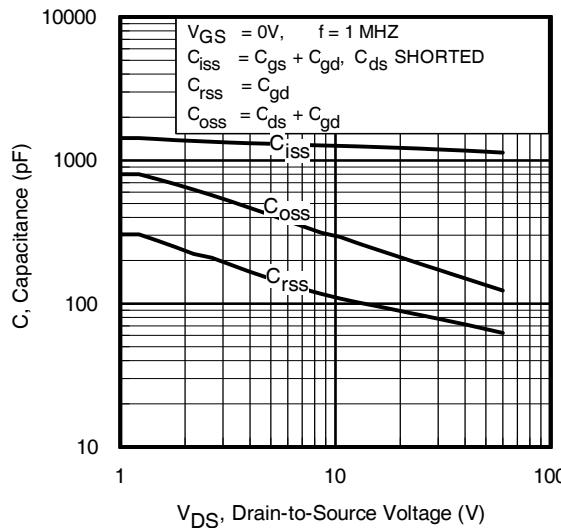
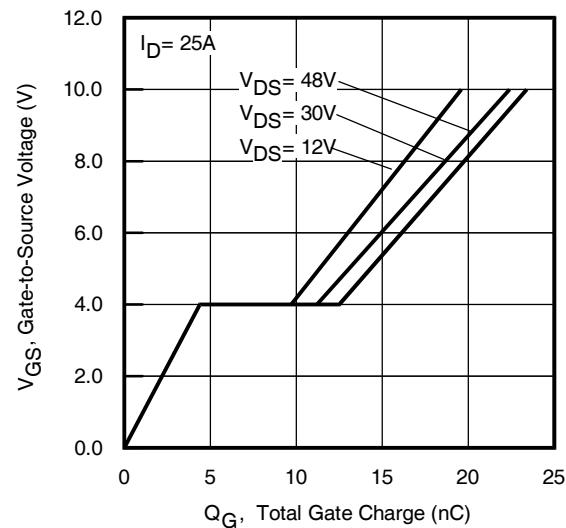
$Q_g$	Total Gate Charge	—	22	30	nC	$I_D = 25\text{A}$
$Q_{gs}$	Gate-to-Source Charge	—	5.0	—		$V_{DS} = 30\text{V}$
$Q_{qd}$	Gate-to-Drain Charge	—	6.3	—		$V_{GS} = 10\text{V}$ ④
$Q_{\text{sync}}$	Total Gate Charge Sync. ( $Q_g - Q_{qd}$ )	—	28.3	—		
$t_{d(on)}$	Turn-On Delay Time	—	6.3	—	ns	$V_{DD} = 39\text{V}$
$t_r$	Rise Time	—	40	—		$I_D = 25\text{A}$
$t_{d(off)}$	Turn-Off Delay Time	—	49	—		$R_G = 20\Omega$
$t_f$	Fall Time	—	47	—		$V_{GS} = 10\text{V}$ ④
$C_{iss}$	Input Capacitance	—	1150	—	pF	$V_{GS} = 0\text{V}$
$C_{oss}$	Output Capacitance	—	130	—		$V_{DS} = 50\text{V}$
$C_{rss}$	Reverse Transfer Capacitance	—	67	—		$f = 1.0\text{MHz}$
$C_{oss \text{ eff. (ER)}}$	Effective Output Capacitance (Energy Related)	—	190	—		$V_{GS} = 0\text{V}, V_{DS} = 0\text{V} \text{ to } 48\text{V}$ ⑥
$C_{oss \text{ eff. (TR)}}$	Effective Output Capacitance (Time Related)	—	230	—		$V_{GS} = 0\text{V}, V_{DS} = 0\text{V} \text{ to } 48\text{V}$ ⑤

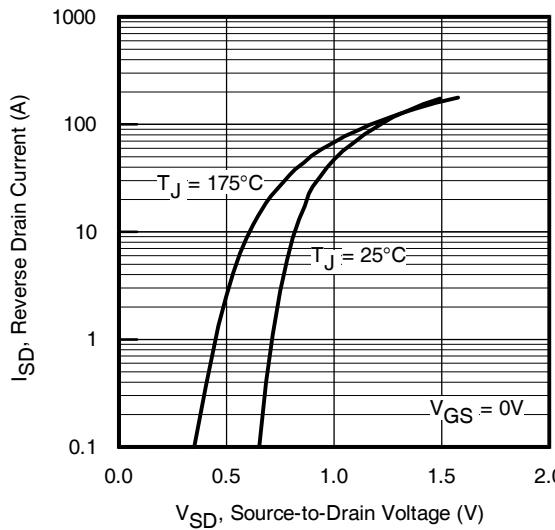
**Diode Characteristics**

	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_s$	Continuous Source Current (Body Diode)	—	—	43	A	MOSFET symbol showing the integral reverse p-n junction diode.
$I_{SM}$	Pulsed Source Current (Body Diode) ①	—	—	170		
$V_{SD}$	Diode Forward Voltage	—	—	1.3	V	$T_J = 25^\circ\text{C}, I_S = 25\text{A}, V_{GS} = 0\text{V}$ ④
$t_{rr}$	Reverse Recovery Time	—	22	33	ns	$T_J = 25^\circ\text{C}$
		—	26	39		$T_J = 125^\circ\text{C}$ $V_R = 51\text{V}$ ,
$Q_{rr}$	Reverse Recovery Charge	—	17	26	nC	$T_J = 25^\circ\text{C}$ $I_F = 25\text{A}$
		—	24	36		$T_J = 125^\circ\text{C}$ $di/dt = 100\text{A}/\mu\text{s}$ ④
$t_{on}$	Forward Turn-On Time	—	1.4	—	A	$T_J = 25^\circ\text{C}$
		Intrinsic turn-on time is negligible (turn-on is dominated by $L_S+L_D$ )				

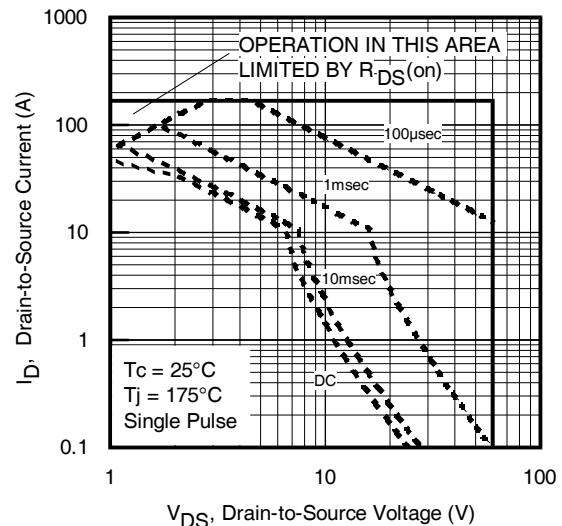

**Notes:**

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Limited by  $T_{J\text{max}}$ , starting  $T_J = 25^\circ\text{C}$ ,  $L = 0.23\text{mH}$ ,  $R_G = 25\Omega$ ,  $I_{AS} = 25\text{A}$ ,  $V_{GS} = 10\text{V}$ . Part not recommended for use above this value.
- ③  $I_{SD} \leq 25\text{A}$ ,  $di/dt \leq 1580\text{A}/\mu\text{s}$ ,  $V_{DD} \leq V_{(\text{BR})\text{DSS}}$ ,  $T_J \leq 175^\circ\text{C}$ .
- ④ Pulse width  $\leq 400\mu\text{s}$ ; duty cycle  $\leq 2\%$ .
- ⑤  $C_{oss \text{ eff. (TR)}}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .
- ⑥  $C_{oss \text{ eff. (ER)}}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .
- ⑦ When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994
- ⑧  $R_\theta$  is measured at  $T_J$  approximately  $90^\circ\text{C}$ .

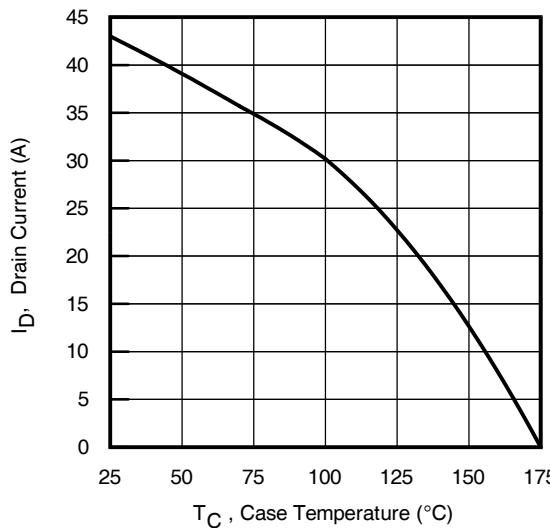

**Fig. 1** Typical Output Characteristics

**Fig. 2** Typical Output Characteristics

**Fig. 3** Typical Transfer Characteristics

**Fig. 4** Normalized On-Resistance vs. Temperature

**Fig 5.** Typical Capacitance vs. Drain-to-Source Voltage

**Fig 6.** Typical Gate Charge vs. Gate-to-Source Voltage



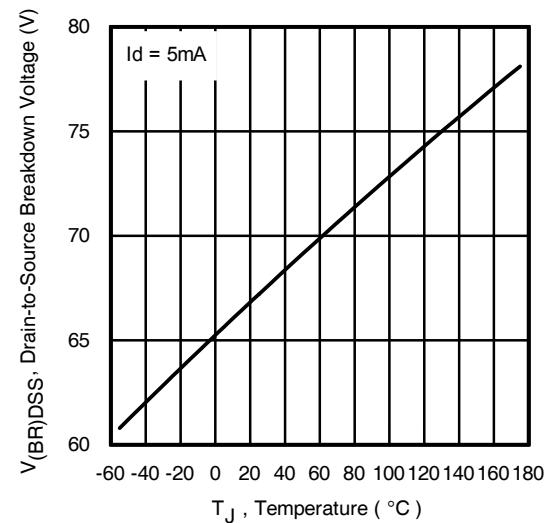
**Fig. 7** Typical Source-to-Drain Diode Forward Voltage



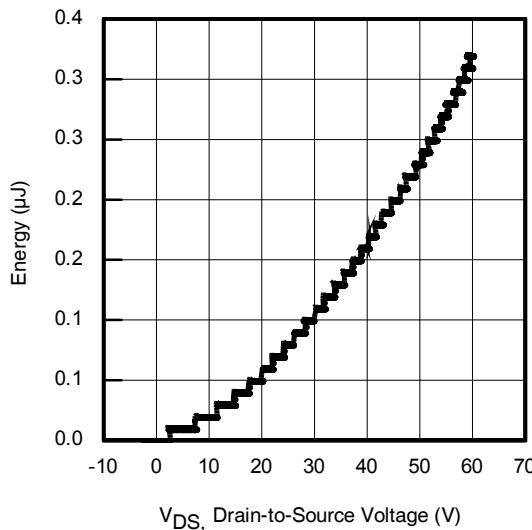
**Fig. 8.** Maximum Safe Operating Area



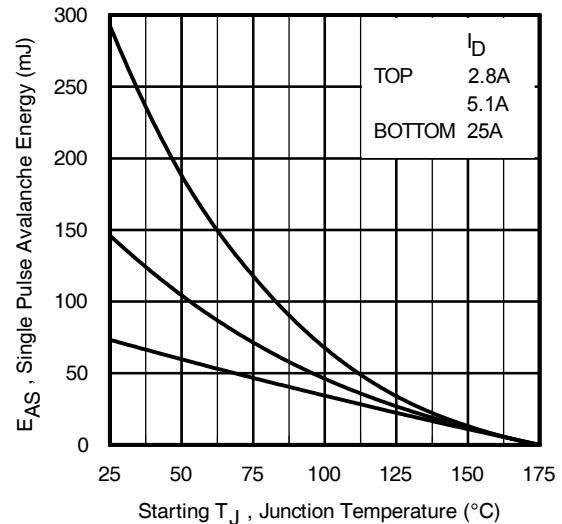
**Fig. 9** Maximum Drain Current vs. Case Temperature



**Fig 10.** Drain-to-Source Breakdown Voltage



**Fig. 11** Typical Coss Stored Energy



**Fig 12.** Maximum Avalanche Energy vs. Drain Current

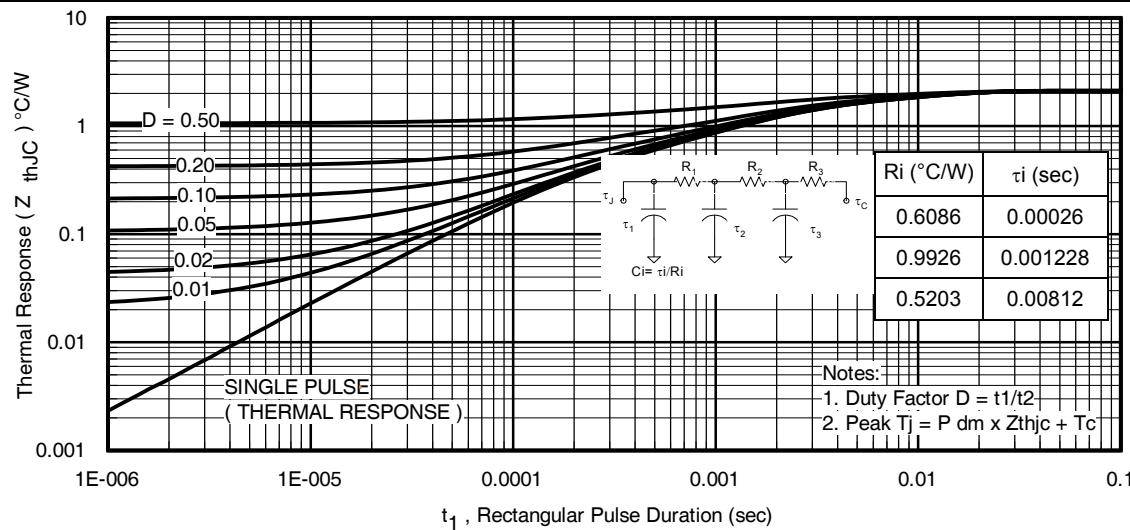


Fig 13. Maximum Effective Transient Thermal Impedance, Junction-to-Case

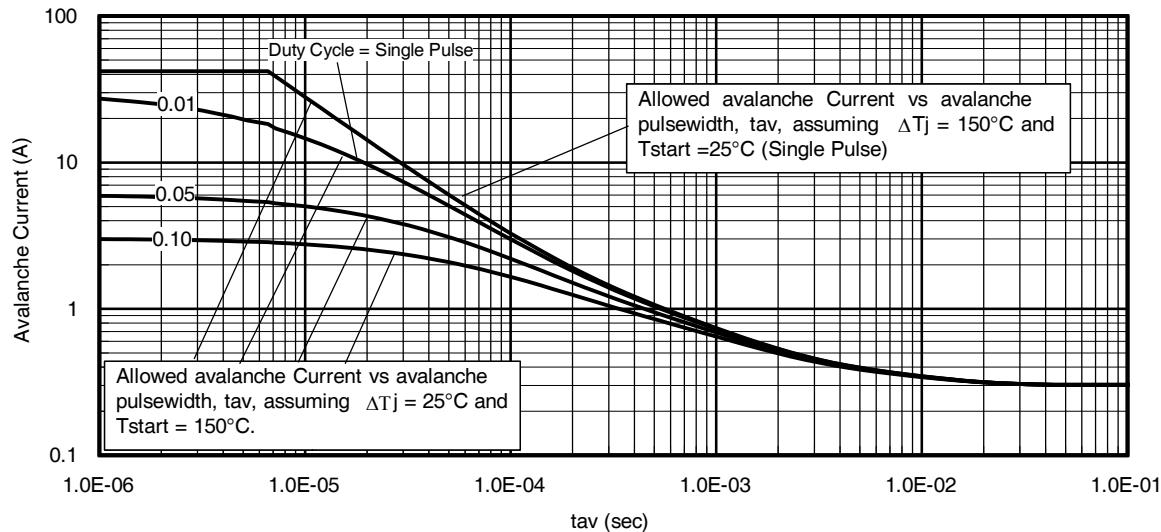


Fig 14. Typical Avalanche Current Vs. Pulse width

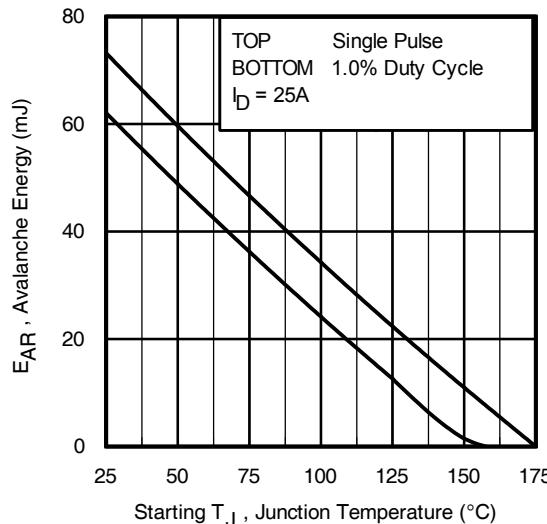


Fig 15. Maximum Avalanche Energy Vs. Temperature

**Notes on Repetitive Avalanche Curves , Figures 14, 15:  
(For further info, see AN-1005 at [www.infineon.com](http://www.infineon.com))**

1. Avalanche failures assumption:  
Purely a thermal phenomenon and failure occurs at a temperature far in excess of  $T_{jmax}$ . This is validated for every part type.
  2. Safe operation in Avalanche is allowed as long as  $T_{jmax}$  is not exceeded.
  3. Equation below based on circuit and waveforms shown in Figures 22a, 22b.
  4.  $P_{D(ave)}$  = Average power dissipation per single avalanche pulse.
  5.  $BV$  = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
  6.  $I_{av}$  = Allowable avalanche current.
  7.  $\Delta T$  = Allowable rise in junction temperature, not to exceed  $T_{jmax}$  (assumed as 25°C in Figure 13, 14).
- $t_{av}$  = Average time in avalanche.  
 $D$  = Duty cycle in avalanche =  $t_{av} \cdot f$   
 $Z_{thJC}(D, t_{av})$  = Transient thermal resistance, see Figures 13)

$$P_{D(ave)} = 1/2 (1.3 \cdot BV \cdot I_{av}) = \Delta T / Z_{thJC}$$

$$I_{av} = 2\Delta T / [1.3 \cdot BV \cdot Z_{th}]$$

$$E_{AS(AR)} = P_{D(ave)} \cdot t_{av}$$

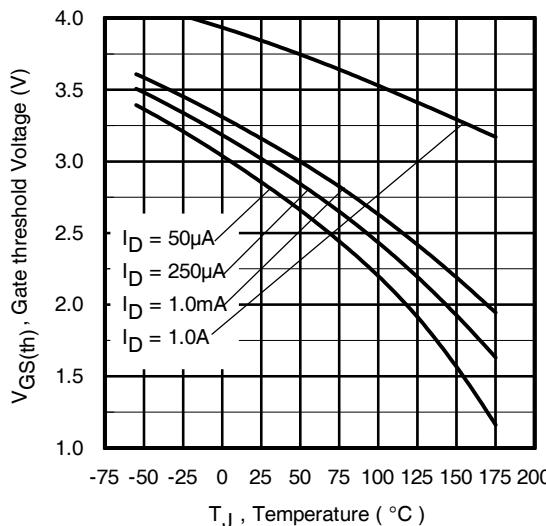


Fig. 16. Threshold Voltage vs. Temperature

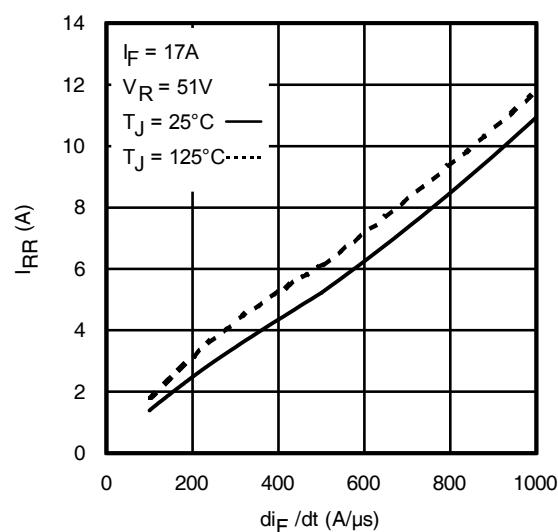


Fig. 17 - Typical Recovery Current vs. diF/dt

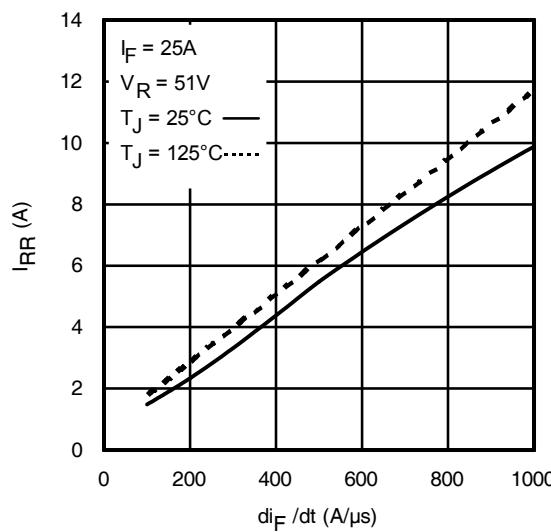


Fig. 18 - Typical Recovery Current vs. diF/dt

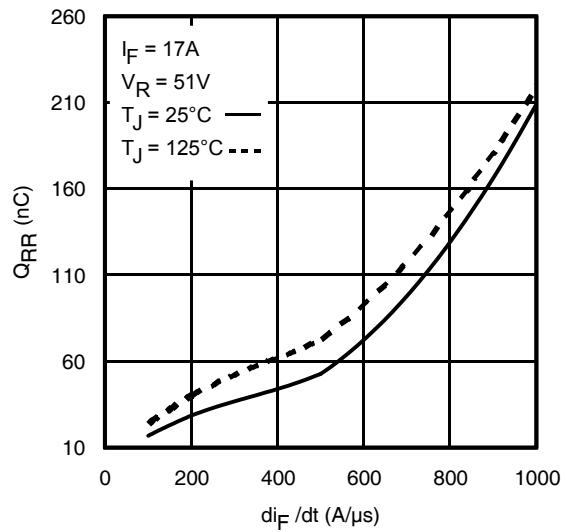


Fig. 19 - Typical Stored Charge vs. diF/dt

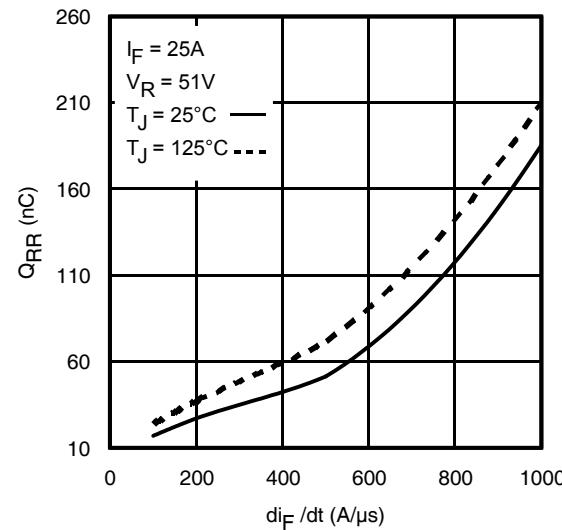
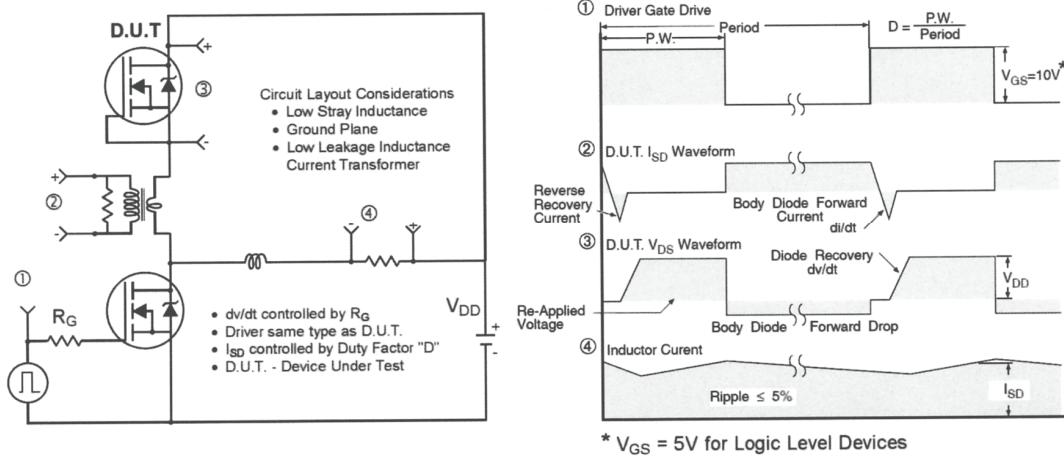
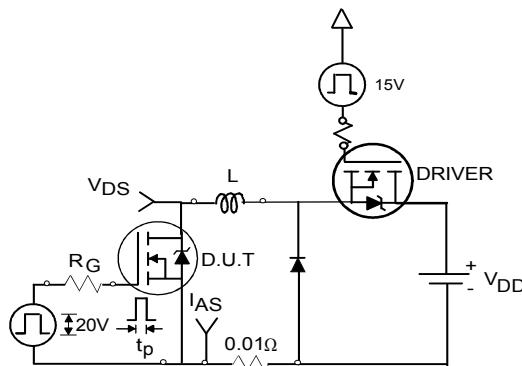


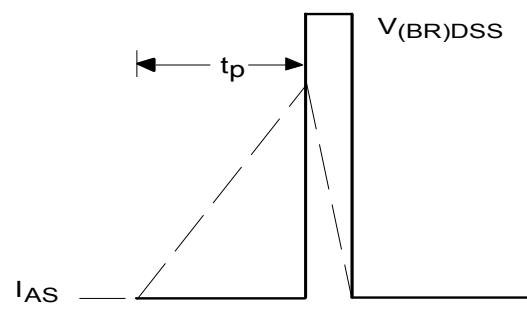
Fig. 20 - Typical Stored Charge vs. diF/dt



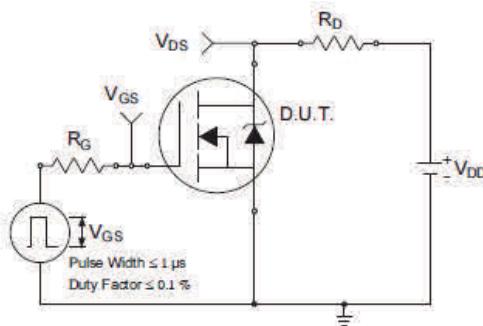
**Fig 20.** Peak Diode Recovery  $dv/dt$  Test Circuit for N-Channel HEXFET® Power MOSFETs



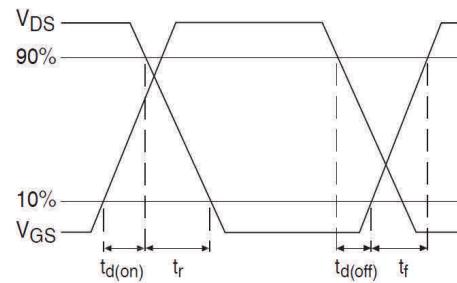
**Fig 21a.** Unclamped Inductive Test Circuit



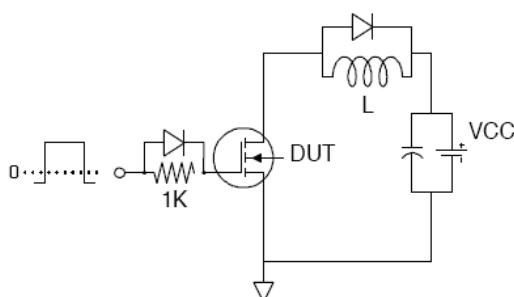
**Fig 21b.** Unclamped Inductive Waveforms



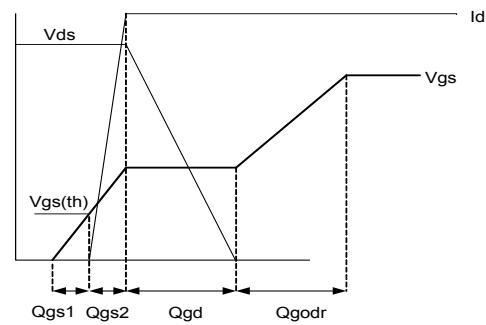
**Fig 22a.** Switching Time Test Circuit



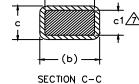
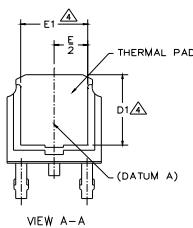
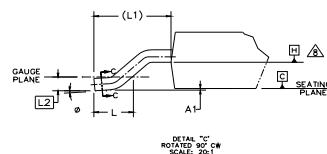
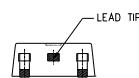
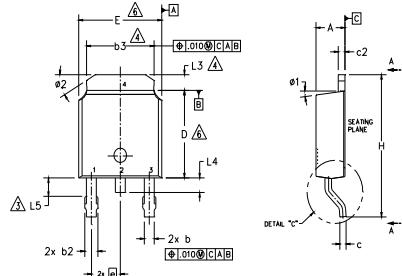
**Fig 22b.** Switching Time Waveforms



**Fig 23a.** Gate Charge Test Circuit



**Fig 23b.** Gate Charge Waveform

**D-Pak (TO-252AA) Package Outline (Dimensions are shown in millimeters (inches))**

## NOTES:

- 1.- DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2.- DIMENSION ARE SHOWN IN INCHES [MILLIMETERS].
- 3.- LEAD DIMENSION UNCONTROLLED IN L5.
- 4.- DIMENSION D1, E1, L3 & b3 ESTABLISH A MINIMUM MOUNTING SURFACE FOR THERMAL PAD.
- 5.- SECTION C-C DIMENSIONS APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN .005 AND 0.10 [0.13 AND 0.25] FROM THE LEAD TIP.
- 6.- DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005 [0.13] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
- 7.- DIMENSION b1 & c1 APPLIED TO BASE METAL ONLY.
- 8.- DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 9.- OUTLINE CONFORMS TO JEDEC OUTLINE TO-252AA.

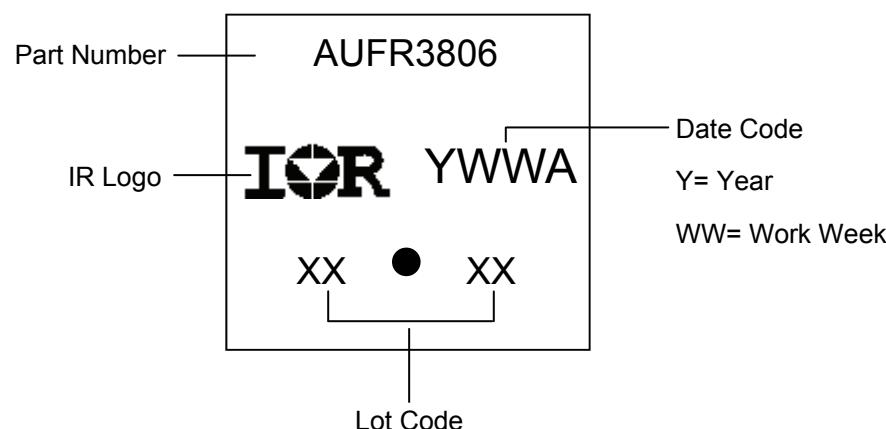
S Y M B O L	DIMENSIONS				N O T E S	
	MILLIMETERS		INCHES			
	MIN.	MAX.	MIN.	MAX.		
A	2.18	2.39	.086	.094		
A1	—	0.13	—	.005		
b	0.64	0.89	.025	.035		
b1	0.65	0.79	.025	.031	7	
b2	0.76	1.14	.030	.045		
b3	4.95	5.46	.195	.215	4	
c	0.46	0.61	.018	.024		
c1	0.41	0.56	.016	.022	7	
c2	0.46	0.89	.018	.035		
D	5.97	6.22	.235	.245	6	
D1	5.21	—	.205	—	4	
E	6.35	6.73	.250	.265	6	
E1	4.32	—	.170	—	4	
e	2.29	BSC	.090	BSC		
H	9.40	10.41	.370	.410		
L	1.40	1.78	.055	.070		
L1	2.74	BSC	.108	REF.		
L2	0.51	BSC	.020	BSC		
L3	0.89	1.27	.035	.050	4	
L4	—	1.02	—	.040		
L5	1.14	1.52	.045	.060	3	
Ø	0°	10°	0°	10°		
Ø1	0°	15°	0°	15°		
Ø2	25°	35°	25°	35°		

LEAD ASSIGNMENTSHEXFET

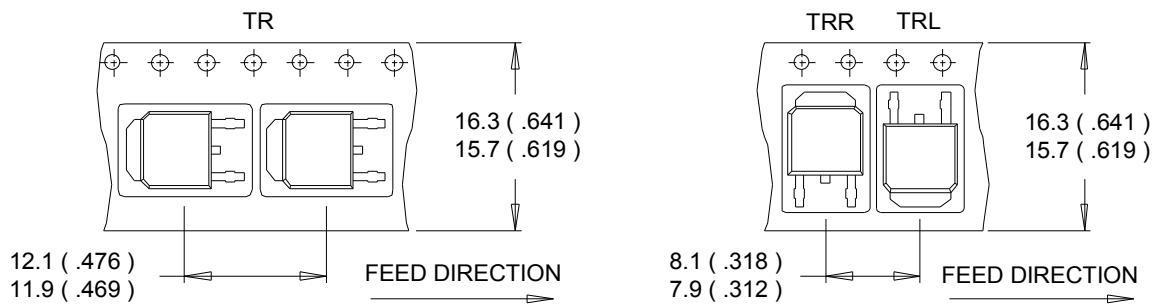
- 1.- GATE
- 2.- DRAIN
- 3.- SOURCE
- 4.- DRAIN

IGBT & CoPAK

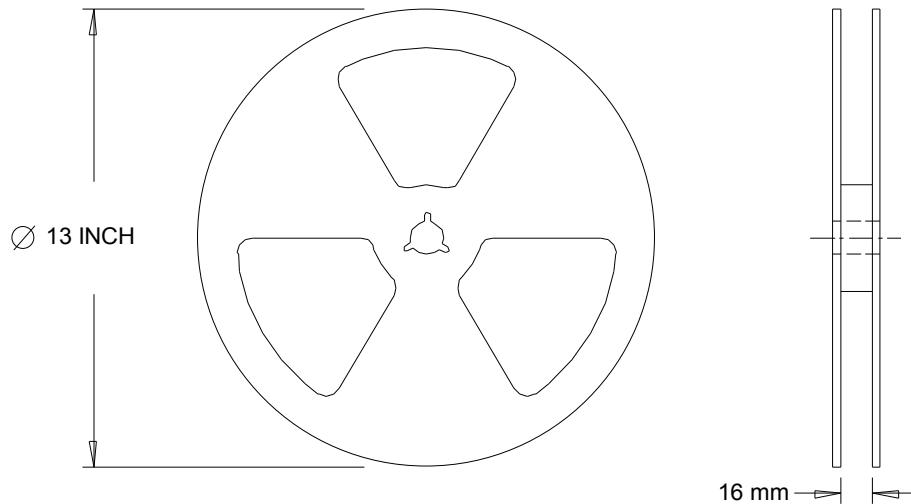
- 1.- GATE
- 2.- COLLECTOR
- 3.- Emitter
- 4.- COLLECTOR

**D-Pak (TO-252AA) Part Marking Information**

Note: For the most current drawing please refer to IR website at <http://www.irf.com/package/>

**D-Pak (TO-252AA) Tape & Reel Information (Dimensions are shown in millimeters (inches))****NOTES :**

1. CONTROLLING DIMENSION : MILLIMETER.
2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS ( INCHES ).
3. OUTLINE CONFORMS TO EIA-481 & EIA-541.

**NOTES :**

1. OUTLINE CONFORMS TO EIA-481.

Note: For the most current drawing please refer to IR website at <http://www.irf.com/package/>

**Qualification Information**

<b>Qualification Level</b>		Automotive (per AEC-Q101)	
		Comments: This part number(s) passed Automotive qualification. Infineon's Industrial and Consumer qualification level is granted by extension of the higher Automotive level.	
<b>Moisture Sensitivity Level</b>		D-Pak	MSL1
<b>ESD</b>	Machine Model	Class M3 (+/- 250V) <sup>†</sup> AEC-Q101-002	
	Human Body Model	Class H1A (+/- 500V) <sup>†</sup> AEC-Q101-001	
	Charged Device Model	Class C5 (+/- 2000V) <sup>†</sup> AEC-Q101-005	
<b>RoHS Compliant</b>		Yes	

<sup>†</sup> Highest passing voltage.

**Revision History**

Date	Comments
11/23/2015	<ul style="list-style-type: none"> <li>• Updated datasheet with corporate template</li> <li>• Corrected ordering table on page 1.</li> <li>• Corrected typo on test condition Coss eff. <math>V_{DS}</math> from "60V" to "48V" on page 2.</li> <li>• Updated typo on the fig.19 and fig.20, unit of y-axis from "A" to "nC" on page 6.</li> <li>• Corrected typo from Rthcs to RthJA (PCB Mount) on page 1.</li> <li>• Corrected typo RthJA from "62C/W" to "110C/W" on page 1.</li> </ul>

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